

Notice of References Cited	Application/Control No. 10/786,005	Applicant(s)/Patent Under Reexamination IDE ET AL.	
	Examiner Edward F. Landrum	Art Unit 3724	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,740,181	05-2004	Lim, Young-Chul	156/73.3
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP- 58-175630	04-1982	Japan	Nakanishi et al	B29 C 17/10
	O	DE	04-1961	Germany	Leinweber	B29 h
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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